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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/781,107	02/18/2004	Chang-Cheng Hung	N1085-00145	1972
54657 DUANE MOE	7590 06/28/2007 DISTID		EXAMINER .	
DUANE MORRIS LLP . IP DEPARTMENT (TSMC)			DESIRE, GREGORY M	
30 SOUTH 17TH STREET PHILADELPHIA, PA 19103-4196		•	ART UNIT	PAPER NUMBER
THEADELT	11111, 171 17103 1170	•	2624	
			MAIL DATÉ	DELIVERY MODE
			06/28/2007	PAPER

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

	Application No.	Applicant(s)				
	10/781,107	HUNG ET AL.				
Office Action Summary	Examiner	Art Unit				
	Gregory M. Desire	2624				
The MAILING DATE of this communication appears on the cover sheet with the correspondence address Period for Reply						
A SHORTENED STATUTORY PERIOD FOR REPLY WHICHEVER IS LONGER, FROM THE MAILING DA - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication. - If NO period for reply is specified above, the maximum statutory period v - Failure to reply within the set or extended period for reply will, by statute Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	ATE OF THIS COMMUNIC. 36(a). In no event, however, may a reposit apply and will expire SIX (6) MONT, cause the application to become ABA	ATION. Note that the state of this communication. NOONED (35 U.S.C. § 133).				
Status	·					
3) Since this application is in condition for alloware closed in accordance with the practice under E	action is non-final. nce except for formal matte	•				
Disposition of Claims						
 4) Claim(s) 1-20 is/are pending in the application. 4a) Of the above claim(s) is/are withdrawn from consideration. 5) Claim(s) is/are allowed. 6) Claim(s) 1-20 is/are rejected. 7) Claim(s) is/are objected to. 8) Claim(s) are subject to restriction and/or election requirement. 						
Application Papers						
9)☐ The specification is objected to by the Examine 10)☒ The drawing(s) filed on 2/18/04 is/are: a)☒ ac Applicant may not request that any objection to the Replacement drawing sheet(s) including the correct 11)☐ The oath or declaration is objected to by the Examine 11.	cepted or b) objected to drawing(s) be held in abeyand tion is required if the drawing(s	e. See 37 CFR 1.85(a). i) is objected to. See 37 CFR 1.121(d).				
Priority under 35 U.S.C. § 119						
12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) All b) Some * c) None of: 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)). * See the attached detailed Office action for a list of the certified copies not received.						
Attachment(s) 1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO/SB/08) Paper No(s)/Mail Date 2/18/04.	Paper No(s)	Immary (PTO-413) /Mail Date ormal Patent Application -				

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DETAILED ACTION

Claim Rejections - 35 USC § 102

1. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

(b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.

2. Claims 1-20 are rejected under 35 U.S.C. 102(b) as being anticipated by Burdorf et al (5,795,688).

Regarding claims 1, 3, 4, 10, 15 and 20 Burdorf discloses,

Acquiring at least one digitized image of at least one mask pattern on the wafer (fig. 2, 18, note col. 3 lines 40-49, examiner interprets the aerial image as acquired digitized image of mask pattern on the wafer);

Converting at least one mask database file for a mask corresponding to the mask pattern into at least one inspection file specific to an inspection tool through an aerial image based processing (fig. 2, 30 note col. 4 lines 8-10, examiner interprets generated simulated aerial image as converted masked file for mask pattern into inspection file through processing aerial image);

Comparing the digitized image (18) and the inspection file (30) by the inspection tool (note col. 4 lines 10-11); and

Detecting disallowed mask patterning process-induced defects by examining differences (note col. 4 lines 11-12, discrepancies are detected).

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Regarding claim 2 Burdorf discloses,

Wherein the design database file is processed with optical proximity correction features (note col. 1 lines 39-41 col. 3 lines 25-30 and 54-57).

Regarding claim 6 Burdorf discloses,

Detecting a proximity trend with the portion of the wafer (note col. 3 lines 54-55)

Regarding claims 7-9, 11-14 Burdorf discloses,

Wherein the detecting further includes detecting defects induced by one or more processes using the mask (note col. 4 lines 20-26).

Regarding claim 16 Burdorf discloses,

Wherein the defects includes critical dimension errors (note fig. 2, 34).

Regarding claim 17 Burdorf discloses,

Further includes information about critical dimension distribution (note fig. 2, 34 and col. 4 lines 11-12).

Regarding claims 5 and 18 Burdorf discloses,

Further comprising bias fitting the digitized image and/or the inspection file (note col. 3 lines 40-50)

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Regarding claim 19 Burdorf discloses,

Wherein the detecting further includes setting on or more error detection thresholds for avoiding false defects (note col. 3 lines 62-63).

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Gregory M. Desire whose telephone number is (571) 272-7449. The examiner can normally be reached on M-F (6:30-3:00).

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Eileen Lillis can be reached on (571) 272-6928. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

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G.D. June 24, 2007

GREGORY DESIRE PRIMARY EXAMINER

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